



SLLS555C - DECEMBER 2002 - REVISED OCTOBER 2004

# LVDS 4x4 CROSSPOINT SWITCH

### FEATURES

- Signaling Rates >1.5 Gbps per Channel
- Supports Telecom/Datacom and HDTV Video Switching
- Non-Blocking Architecture Allows Each Output to be Connected to Any Input
- Compatible With ANSI TIA/EIA-644-A LVDS Standard
- 25 mV of Input Voltage Threshold Hysteresis
- Propagation Delay Times, 900 ps Typical
- Inputs Electrically Compatible With LVPECL, CML and LVDS Signal Levels
- Operates From a Single 3.3-V Supply
- Integrated 110-Ω Line Termination Resistors Available With SN65LVDT125

#### **APPLICATIONS**

- Clock Buffering / Clock Muxing
- Wireless Base Stations
- High-Speed Network Routing
- HDTV Video Switching

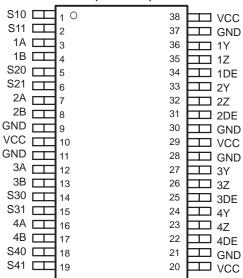
### DESCRIPTION

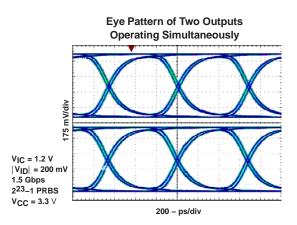
The SN65LVDS125 and SN65LVDT125 are 4x4 nonblocking crosspoint switches. Low-voltage differential signaling (LVDS) is used to achieve signaling rates of 1.5 Gbps per channel. Each output driver includes a 4:1 multiplexer to allow any input to be routed to any output. Internal signal paths are fully differential to achieve the high signaling speeds while maintaining low signal skews. The SN65LVDT125 incorporates 110- $\Omega$  termination resistors for those applications where board space is a premium.

Designed to support signaling rates up to 1.5 Gbps for OC-12 clocks (622 MHz). The 1.5-Gbps signaling rate allows use in HDTV systems, including SMPTE 292 video applications requiring signaling rates of 1.485 Gbps.

The SN65LVDS125 and SN65LVDT125 are characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

#### SN65LVDS125DBT (Marked as LVDS125) SN65LVDT125DBT (Marked as LVDT125) (TOP VIEW)







Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

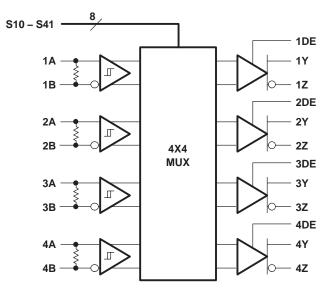


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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

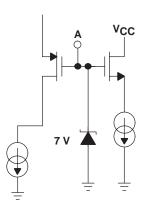
### LOGIC DIAGRAM

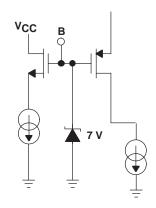


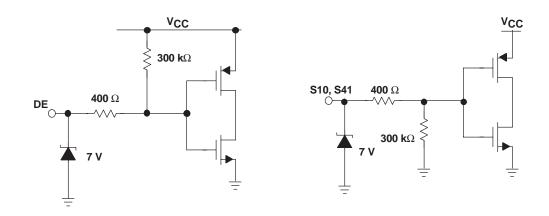
Integrated 110- $\Omega$  Termination on LVDT Only



## EQUIVALENT INPUT AND OUTPUT SCHEMATIC DIAGRAMS

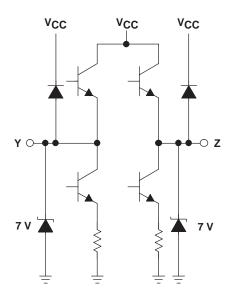






**INPUT LVDS125** 

OUTPUT LVDS125



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CROSSPOINT LOGIC TABLES
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OL	OUTPUT CHANNEL 1			OUTPUT CHANNEL 2			OUTPUT CHANNEL 3			JTPUT C	HANNEL 4
	TROL NS	INPUT SELECTED		TROL NS	INPUT SELECTED	CON Pli	-	INPUT SELECTED		TROL NS	INPUT SELECTED
S10	S11	1Y/1Z	S20	S21	2Y/2Z	S30	S31	3Y/3Z	S40	S41	4Y/4Z
0	0	1A/1B	0	0	1A/1B	0	0	1A/1B	0	0	1A/1B
0	1	2A/2B	0	1	2A/2B	0	1	2A/2B	0	1	2A/2B
1	0	3A/3B	1	0	3A/3B	1	0	3A/3B	1	0	3A/3B
1	1	4A/4B	1	1	4A/4B	1	1	4A/4B	1	1	4A/4B

#### PACKAGE DISSIPATION RATINGS

PACKAGE	CIRCUIT BOARD	$T_A \le 25^{\circ}C POWER$	DERATING FACTOR <sup>(1)</sup>	T <sub>A</sub> = 85°C POWER
	MODEL	RATING	ABOVE T <sub>A</sub> = 25°C	RATING
TSSOP (DBT)	High–K <sup>(2)</sup>	1772 mW	15.4 mW/°C	847 mW

 $\overline{(1)}$  This is the inverse of the junction-to-ambient thermal resistance when board-mounded and with no air flow.

(2) In accordance with the High-K thermal metric definitions of EIA/JESD51-6

#### THERMAL CHARACTERISTICS

	PARAMETER		TEST CONDITIONS	VALUE	UNITS
θJB	Junction-to-board thermal resista	nce		40.3	
θJC	C Junction-to-case thermal resistance			8.5	°C/W
_	Device a survey disation for	Typical	$V_{CC} = 3.3 \text{ V}, \text{ T}_{A} = 25^{\circ}\text{C}, 750 \text{ MHZ}$	356	mW
PD	Device power dissipation	Maximum	$V_{CC} = 3.6 \text{ V}, \text{ T}_{A} = 85^{\circ}\text{C}, 750 \text{ MHZ}$	522	mW

#### ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted<sup>(1)</sup>

			UNITS			
Supply voltage range, v <sub>CC</sub>			–0.5 V to 4 V			
	–0.5 V to 4 V					
Maltana na s	(A, B)	(A, B)				
Voltage range	Je VA – VBI (LVDT only)		1 V			
	(Y, Z)		–0.5 V to 4 V			
	Human body model <sup>(3)</sup>	All pins	±3 kV			
Electrostatic discharge	Charged-device model <sup>(4)</sup>	All pins	±500 V			
Continuous power dissipation	· · ·		See Dissipation Rating Table			
Storage temperature range			−65°C to 150°C			

(1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

(3) Tested in accordance with JEDEC Standard 22, Test Method A114-A.

(4) Tested in accordance with JEDEC Standard 22, Test Method C101.

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## **RECOMMENDED OPERATING CONDITIONS**

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>		3	3.3	3.6	V
High-level input voltage, VIH	S10-S41, 1DE-4DE	2			V
Low-level input voltage, VIL	S10-S41, 1DE-4DE			0.8	V
	LVDS	0.1			V
Magnitude of differential input voltage $ V_{\mbox{\scriptsize ID}} $	LVDT	0.1		0.8	V
Input voltage (any combination of commo	n-mode or input signals)	0		3.3	V
Junction temperature, TJ				140	°C
Operating free-air temperature, $T_A$ (1)		-40		85	°C
4)					

(1) Maximum free-air temperature operation is allowed as long as the device maximum junction temperature is not exceeded.

### TIMING SPECIFICATIONS

	PARAMETER				MAX	UNIT
<sup>t</sup> SET	Input to select setup time			0.6		ns
<sup>t</sup> HOLD	Input to select hold time	See Figure 7		0.2		ns
<b>t</b> SWITCH	Select to switch output			1.2	1.6	ns

### INPUT ELECTRICAL CHARACTERISTICS

over recommended operating conditions unless otherwise noted (1)

	PARAMETER		TEST CONDITIONS	MIN	TYP(1)	MAX	UNIT	
V <sub>IT+</sub>	Positive-going differential input voltage threshold		See Figure 1			100	mV	
V <sub>IT-</sub>	Negative-going differential input voltage threshold		See Figure 1	-100			mV	
VID(HYS)	Differential input voltage hysteresis				25		mV	
ΊΗ	High-level input current	1DE-4DE S10-S41	V <sub>IH</sub> = 2 V			-10 20	μΑ	
۱	Low-level input current	1DE-4DE S10-S41	V <sub>IL</sub> = 0.8 V			-10 20	μA	
lj	Input current		V <sub>I</sub> = 0 V or 3.3 V, second input at 1.2 V (other input open for LVDT)	-20		20	μΑ	
l <sub>l(OFF)</sub>	Input current		$V_{CC} \le 1.5 \text{ V}, \text{ V}_{I} = 0 \text{ V or } 3.3 \text{ V},$ second input at 1.2 V (other input open for LVDT)	-20		20	μΑ	
lIO	Input offset current ( I <sub>IA</sub> - I <sub>IB</sub>  ) ('I	VDS)	$V_{IA} = V_{IB}, 0 \le V_{IA} \le 3.3 \text{ V}$	-6		6	μA	
P_	Termination resistance ('LVDT)		V <sub>ID</sub> = 300 mV, V <sub>IC</sub> = 0 V to 3.3 V	90	110	132	0	
RT	Termination resistance('LVDT with power-off)		$V_{ID}$ = 300 mV, $V_{IC}$ = 0 V to 3.3 V, $V_{CC}$ = 1.5 V	90	110	132	Ω	
CT	Differential input capacitance				0.6		pF	

(1) All typical values are at 25°C and with a 3.3 V supply.

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**OUTPUT ELECTRICAL CHARACTERISTICS** 

over recommended operating conditions unless otherwise noted<sup>(1)</sup>

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V <sub>OD</sub>	Differential output voltage magnitude	See Figure 2	247	350	454	mV
$\Delta  V_{OD} $	Change in differential output voltage magnitude between logic states	$V_{ID} = \pm 100 \text{ mV}$	-50		50	mV
VOC(SS)	Steady-state common-mode output voltage		1.125		1.375	V
$\Delta V_{OC}(SS)$	Change in steady-state common-mode output voltage between logic states	See Figure 3	-50		50	mV
VOC(PP)	Peak-to-peak common-mode output voltage			50	150	mV
ICC	Supply current	$R_L=100\Omega$ , $C_L=1  pF$		107	145	mA
los	Short-circuit output current	$V_{OY}$ or $V_{OZ} = 0 V$	-27		27	mA
IOSD	Differential short circuit output current	V <sub>OD</sub> = 0 V	-12		12	mA
IOZ	High-impedance output current	AO = 0 A  or  ACC	-1		±1	μA
СО	Differential output capacitance			1.2		pF

#### SWITCHING CHARACTERISTICS

over recommended operating conditions unless otherwise noted<sup>(1)</sup>

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<sup>t</sup> PLH	Propagation delay time, low-to-high-level output		700	900	1200	
<sup>t</sup> PHL	Propagation delay time, high-to-low-level output		700	900	1200	
tr	Differential output signal rise time (20%-80%)	See Figure 4		210	255	ps
tf	Differential output signal fall time (20%-80%)			210	255	
<sup>t</sup> sk(p)	Pulse skew ( tp <sub>HL</sub> – tp <sub>LH</sub>  ) <sup>(1)</sup>			0	50	ps
<sup>t</sup> sk(o)	Channel-to-channel output skew(2)				150	ps
<sup>t</sup> sk(pp)	Part-to-part skew <sup>(3)</sup>				300	ps
<sup>t</sup> jit(per)	Period jitter, rms (1 standard deviation) <sup>(4)</sup>	750 MHz clock input <sup>(5)</sup> (see Figure 6)		0.4	3	ps
<sup>t</sup> jit(cc)	Cycle-to-cycle jitter (peak) <sup>(4)</sup>	750 MHz clock input <sup>(6)</sup> (see Figure 6)		4.7	13	ps
<sup>t</sup> jit(pp)	Peak-to-peak jitter <sup>(4)</sup>	1.5 Gbps 2 <sup>23</sup> –1 PRBS input <sup>(7)</sup> (see Figure 6)		65	110	ps
<sup>t</sup> jit(det)	Deterministic jitter, peak-to-peak <sup>(4)</sup>	1.5 Gbps 2 <sup>7</sup> –1 PRBS input <sup>(8)</sup> (see Figure 6)		56	90	ps
<sup>t</sup> PHZ	Propagation delay, high-level-to-high-impedance output				6	
<sup>t</sup> PLZ	Propagation delay, low-level-to-high-impedance output				6	
<sup>t</sup> PZH	Propagation delay, high-impedance -to-high-level output	See Figure 5			50	ns
tpzl	Propagation delay, high-impedance-to-low-level output				50	

(1)  $t_{sk(p)}$  is the magnitude of the time difference between the  $t_{PLH}$  and  $t_{PHL}$  of any output of a single device.

(2)  $t_{sk(0)}$  is the maximum delay time difference between drivers over temperature, V<sub>CC</sub>, and process.

(3) t<sub>sk(pp)</sub> is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

(4) Jitter specifications are based on design and characteriztion. Stimulus system jitter of 1.9 ps tjit(per), 16 ps tjit(cc). 17 ps tjit(pp), and 7.2 ps tjit(det) have been subtracted from the values.

(5) Input voltage =  $V_{ID}$  = 200 mV, 50% duty cycle at 750 MHz,  $t_{f}$  =  $t_{f}$  = 50 ps (20% to 80%), measured over 1000 samples. (6) Input voltage =  $V_{ID}$  = 200 mV, 50% duty cycle at 750 MHz,  $t_{f}$  =  $t_{f}$  = 50 ps (20% to 80%). (7) Input voltage =  $V_{ID}$  = 200 mV, 2<sup>23</sup>–1 PRBS pattern at 1.5 Gbps,  $t_{f}$  =  $t_{f}$  = 50 ps (20% to 80%), measured over 200k samples. (8) Input voltage =  $V_{ID}$  = 200 mV, 2<sup>7</sup>–1 PRBS pattern at 1.5 Gbps,  $t_{f}$  =  $t_{f}$  = 50 ps (20% to 80%).

#### PARAMETER MEASUREMENT INFORMATION

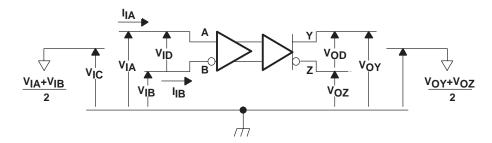


Figure 1. Voltage and Current Definitions

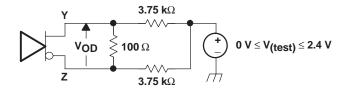
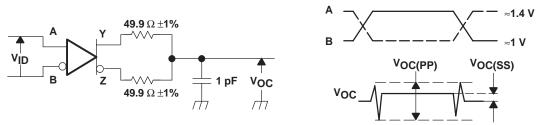
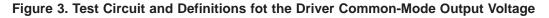
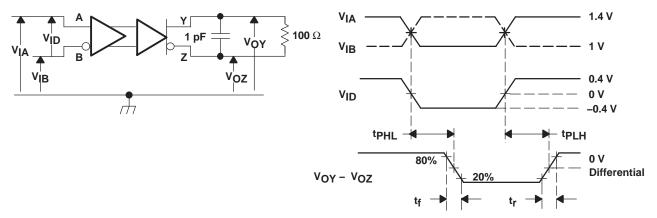


Figure 2. Differential Output Voltage (V<sub>OD</sub>) Test Circuit



NOTE: All input pulses are supplied by a generator having the following characteristics:  $t_f$  or  $t_f \le 1$  ns, pulse-repetition rate (PRR) = 0.5 Mpps, pulse width = 500 ±10 ns;  $R_L$  = 100W;  $C_L$  includes instrumentation and fixture capacitance within 0,06 mm of the D.U.T.;the measurement of V<sub>OC</sub>(PP) is made on test equipment with a –3 dB bandwidth of at least 300 MHz.



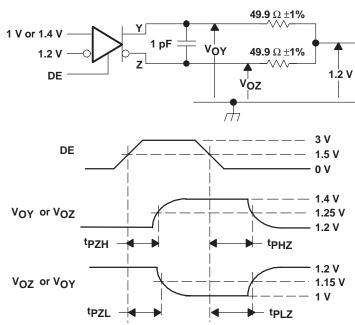


NOTE: All input pulses are supplied by a generator having the following characteristics:  $t_f$  or  $t_f \le .25$  ns, pulse-repetition rate (PRR) = 0.5 Mpps, pulse width = 500 ± 10 ns .  $C_1$  includes instrumentation and fixture capacitance within 0,06 mm of the D.U.T.



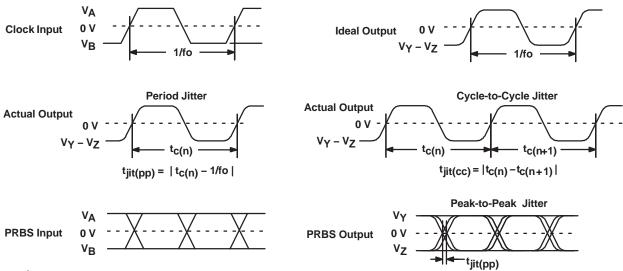
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NOTE: A. All input pulses are supplied by a generator having the following characteristics:  $t_f$  or  $t_f \le 1$  ns, pulse-repetition rate (PRR) = 0.5 Mpps, pulse width = 500 ± 10 ns . CL includes instrumentation and fixture capacitance within 0,06 mm of the D.U.T.

#### Figure 5. Enable and Disable Time Circuit and Definitions

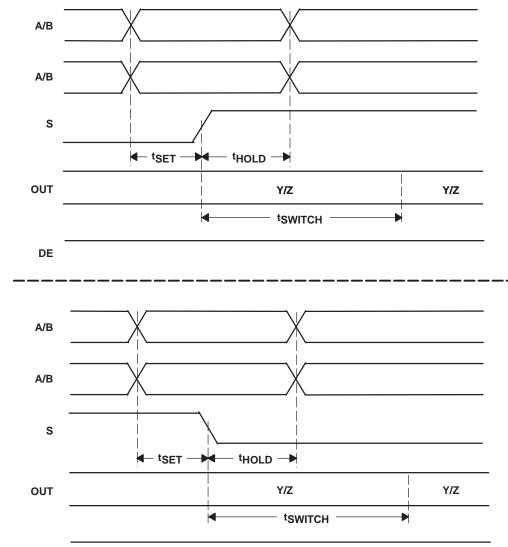


NOTE: A. All input pulses are supplied by an Agilent 81250 Stimulus System. NOTE: B. The measurement is made on a TEK TDS6604 running TDSJIT3 application software.

Figure 6. Driver Jitter Measurement Waveforms



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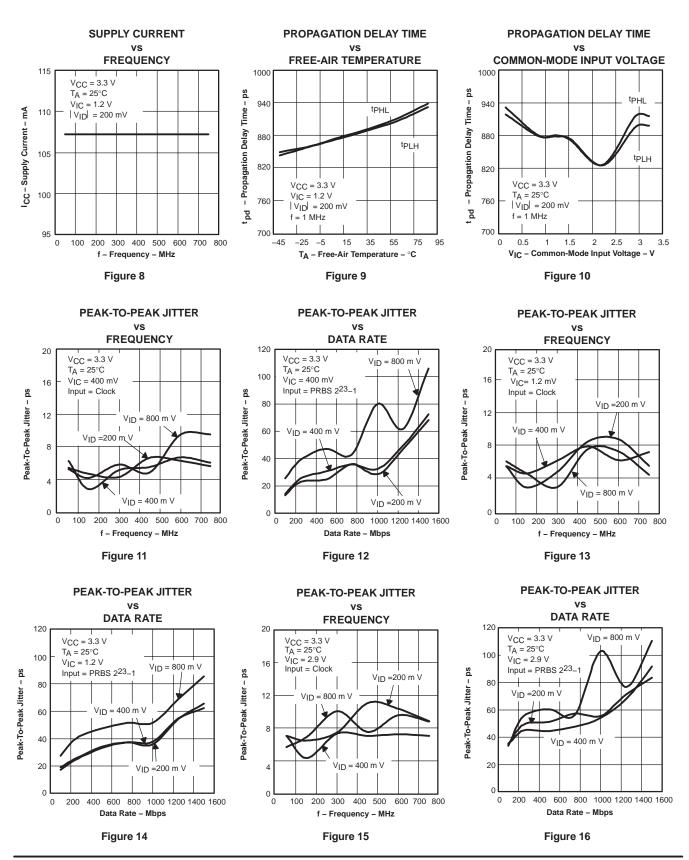
NOTE: t<sub>SET</sub> and t<sub>HOLD</sub> times specify that data must be in a stable state before and after mux control switches.

#### Figure 7. Input to Select for Both Rising and Falling Edge Setup and Hold Times

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#### **TYPICAL CHARACTERISTICS**



TEXAS INSTRUMENTS www.ti.com

**SN65LVDT125** SLLS555C – DECEMBER 2002 – REVISED OCTOBER 2004

**SN65LVDS125** 

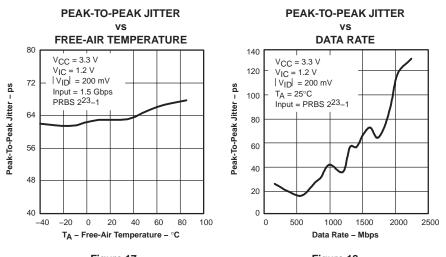


Figure 17



DIFFERENTIAL OUTPUT VOLTAGE

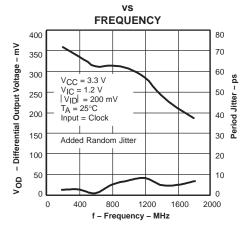
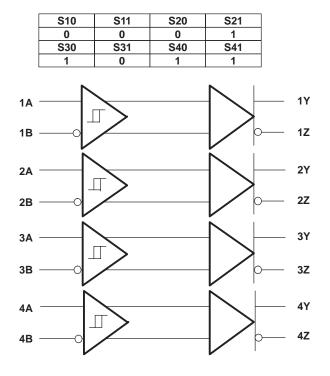


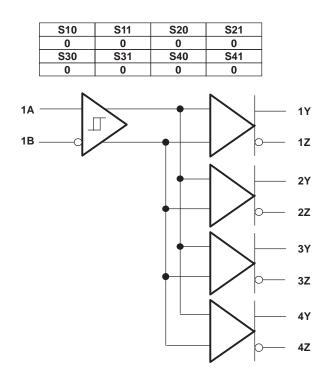
Figure 19

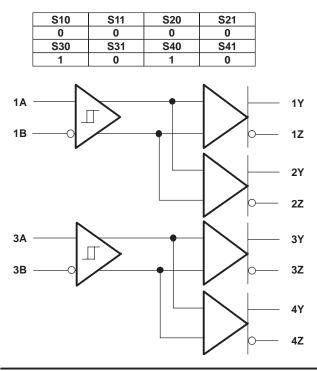


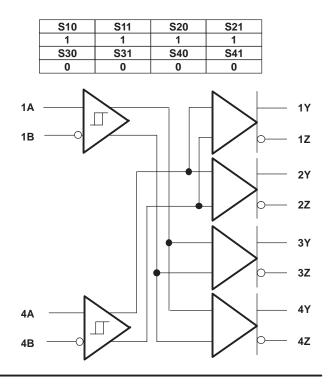
#### **APPLICATION INFORMATION**

#### **CONFIGURATION EXAMPLES**





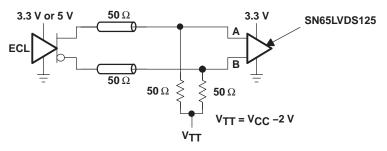






#### **APPLICATION INFORMATION**

TYPICAL APPLICATION CIRCUITS (ECL, PECL, LVDS, ETC.)





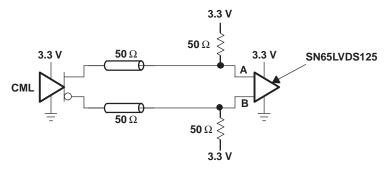


Figure 21. Current-Mode Logic (CML)

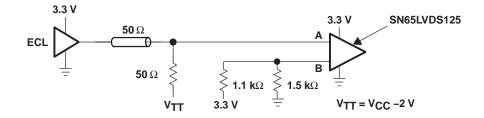


Figure 22. Single-Ended (LVPECL)

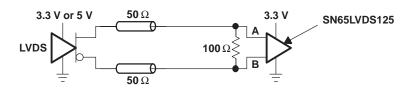


Figure 23. Low-Voltage Differential Signaling (LVDS)

#### PACKAGING INFORMATION

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins Package Qty	Eco Plan <sup>(2)</sup>	Lead/Ball Finish	MSL Peak Temp <sup>(3)</sup>
SN65LVDS125DBT	NRND	TSSOP	DBT	38	TBD	Call TI	Call TI
SN65LVDS125DBTR	NRND	TSSOP	DBT	38	TBD	Call TI	Call TI
SN65LVDT125DBT	NRND	TSSOP	DBT	38	TBD	Call TI	Call TI
SN65LVDT125DBTR	NRND	TSSOP	DBT	38	TBD	Call TI	Call TI

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details. TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

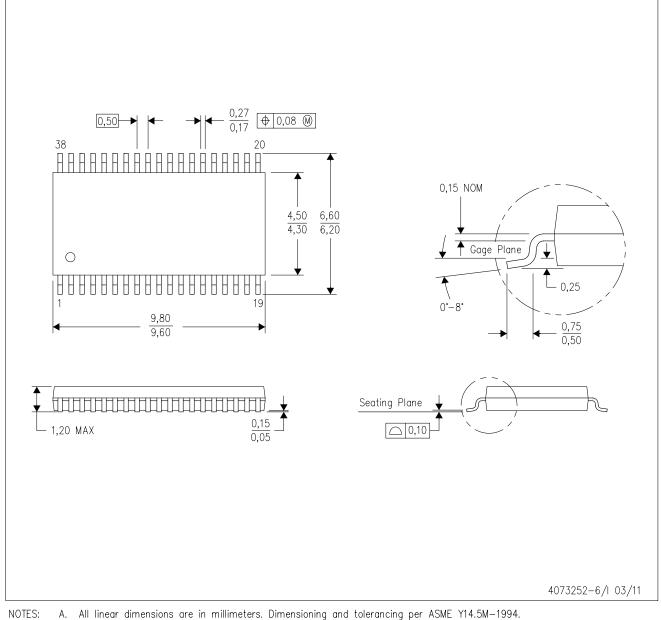
<sup>(3)</sup> MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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DBT (R-PDSO-G38)

PLASTIC SMALL OUTLINE



B. This drawing is subject to change without notice.

- C. Body dimensions do not include mold flash or protrusion.
- D. Falls within JEDEC MO-153.



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